Nuclear Data Evaluation and Testing for Nuclear Criticality Safety Applications

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Outline

Introduction

Benchmark Identification and Modeling

Results

Summary and conclusion

Acknowledgement



Objective

- Identify benchmark experiments for cross section evaluation for NCS purposes, with specified materials of interest
- Model selected benchmarks in CE SCALE and MCNP, obtaining criticality results for comparison of cross section libraries ENDF 7.1 and ENDF 8
- Gauge and test recent nuclear data evaluations, providing feedback on performance



Introduction

- Benchmark identification is done in reference to the NCSP 5 year plan, with materials of interest recently completed evaluations
 - Ca; Co-59; Cu-63, 65; Ni-58, 60; W-182,183,184,186
 - Lucite, Polyethylene, Beryllium, Beryllium Oxide, Crystal Graphite, Reactor Graphite, Silicon Carbide, Silicon Dioxide, Uranium Dioxide, Uranium Nitride, Hexagonal Ice, Yttrium Hydride
- Criticality sensitivities are used to find relevant benchmarks, as sensitive benchmarks will be susceptible to change, if at all
- Takes into account: geometry of material, material number density, flux spectrum of benchmark
- Provides comprehensive view of benchmark dependence on XS



Identification and Modeling

- For isotope sensitivity, direct use of DICE(included in ICSBEP Handbook)
- For XS updates, direct ENDF data
- Alignment of sensitivity and XS change for greatest expected change
- Models constructed from Section 3 of ICSBEP benchmark evaluation
- Materials listed in natural abundance are decomposed to constituent isotopes, as ACE ENDF 8 libraries are not available as natural



HMI-006 Cu-63 Scattering Sensitivity(Grey) Cu-63 Scattering XS, Ratio ENDF8/ENDF7(Black)



HEU Metal Intermediate-006

- Identified for high sensitivity to Copper XS
 Of further interest is presence of Graphite
 HEU metal discs(green) interspersed with Graphite discs(yellow), surrounded by Copper reflector(red)
- 4 cases; decreasing number of Graphite plates
- Uniform disc heights, homogenous material without impurities





HEU Metal Intermediate-006

- Both codes use CE data;
 difference in Δk is <3σ as expected
- For this benchmark, Cases 1,2,4 trend closer to criticality with ENDF 8
- Benchmark Model Uncertainty: 80-90 pcm (Experimental Uncertainty + Simplification bias)

KENO							
	Case	ENDF/B- VII.1(±10)*	Case	ENDF/B-VIII(±10)*	∆k(pcm)		
3 n	1	0.993069	1	0.995474	241±14		
	2	0.997005	2	1.000188	318±14		
	3	1.000661	3	1.002886	222±14		
	4	1.005685	4	1.003687	-199±14		
	MCNP						
	Case	ENDF/B- VII.1(±4)*	Case	ENDF/B-VIII(±4)*	∆k(pcm)		
	1	0.99294	1	0.99584	290±6		
	2	0.99689	2	1.00027	338±6		
	3	1.00076	3	1.00325	249±6		
	4	1.0073	4	1.00537	-193±6		



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Identified for high sensitivity to Copper XS • Of further interest is presence of HDPE(Case 3) HEU metal discs(black) interspersed with Graphite discs(green), surrounded by Copper reflector(orange) 3 cases; Case 2 reduced reflector height, Case 3 added HDPE and reduced core height Nonuniform disc heights, heterogenous material





with impurities

- All 3 cases trend closer toward criticality
- Case 1&2 significantly so

Benchmark Model Uncertainty:

Cases 1&2: 240 pcm Case 3: 690 pcm

		KENO		
Case	ENDF/B- VII.1(±10)*	Case	ENDF/B- VIII(±10)*	Δk(pcm)
1	1.008343	1	1.00412	-422±14
2	1.009737	2	1.00571	-403±14
3	1.012348	3	1.011367	-98±14

MCNP ENDF/B-ENDF/B-Case $\Delta k(pcm)$ Case VII.1(±3)* VIII(±3)* 1 1.00853 1 1.00397 -456±4 2 2 1.00955 1.00481 -474±4 3 1.01236 3 1.01146 -90 ± 4



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Identified for high sensitivity to Copper XS HEU metal discs(dark green) surrounded by HEU metal rings(light green), surrounded by Copper reflector(yellow, orange, pink) No impurities, individual fuel segments homogenous. Reflector material split into individually homogenous Top, Lower, Inner(Side), Outer(Side)





ENDF 8 significantly improves results- closer to criticality KENO

 Benchmark Model Uncertainty: 160 pcm

ILEI (O					
Case	ENDF/B- VII.1(±10)*	Case	ENDF/B- VIII(±10)*	Δk(pcm)	
1	1.011515	1	1.00334	-818±14	

		MCNP		
Case	ENDF/B- VII.1(±3)*	Case	ENDF/B- VIII(±3)*	∆k(pcm)
1	1.01134	1	1.00284	-850±4





Concentric spheres of HEU and:

- 1. Copper*
- 2. Copper*
- 3. Cast iron
- 4. Nickel-Copper-Zinc-alloy*
- 5. Thorium
- 6. Tungsten alloy*





- Cases 2, 3, 5, and 6 improve with ENDF 8
- While Case 3&5 are not of explicit interest, exhibit XS improvement
- Mixed results for those of interest;
 1 instance of Copper improves, the other does not. Ni-Cu alloy worse as well

			KENO			
	Case	ENDF/B- VII.1(±10)*	Case	ENDF/B- VIII(±10)*	∆k(pcm)	
	1	1.000285	1	0.994822	-546±14	
	2	1.004361	2	0.996746	-762±14	
	3	0.995251	3	0.998475	322±14	
	4	0.999946	4	0.995283	-466±14	
	5	1.000582	5	1.000428	-15±14	
	6	1.00577	6	1.003567	-220±14	
MCNP						
	Case	ENDF/B- VII.1(±3)*	Case	ENDF/B- VIII(±3)*	∆k(pcm)	
	1	1.00006	1	0.99462	-544±4	
e	2	1.00436	2	0.99677	-759±4	
Ŭ	3	0.99609	3	0.99854	245±4	
	4	0.9998	4	0.99518	-462±4	
	5	1.00041	5	1.00035	-6±4	
	6	1.00606	6	1.0035	-256±4	

Benchmark Model Uncertainty: 300 pcm



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Summary and conclusions

- 11 Benchmark cases with Copper, of which 8 show improvement, 6 with significant improvement
- 4 Benchmark cases with Graphite, of which 3 show significant improvement
- 1 with Polyethylene, Tungsten, Nickel, with respective improvement, improvement, and worsening
- While still too early to draw conclusions, 11 out of 14 total evaluated cases showed improvement over ENDF 7.1 XS



Modeling in Progress: HMF-084

Series of nested HEU and reflector cylinders
Impurities and structural material ignored
Copper, Nickel, Cobalt, Poly, Tungsten





Future Modeling

- HST-007; Ca
- PMF-005, -013, -014, -040; All Cu/Ni
- HMF-003, -049, -050; All W
- Search for more evaluations with thermal scattering compounds



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Questions?

